EPC2308 – Enhancement Mode Power Transistor

 V_{DS} , 150 V $R_{DS(on)}$, 6 m Ω max









Revised December 19, 2024

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Application Notes:

- Easy-to-use and reliable gate, Gate Drive ON = 5 V typical, OFF = 0 V (negative voltage not needed)
- Top of FET is electrically connected to source

Questions:
Ask a GaN
Expert



	Maximum Ratings					
	PARAMETER VALUE UNIT					
V	Drain-to-Source Voltage (Continuous)	150	v			
V _{DS}	Drain-to-Source Voltage (Repetitive Transient) (1)	180	\ \			
I _D	Continuous (T _J ≤125°C)	63	^			
	Pulsed (25 °C, T _{PULSE} = 300 μs)	157	Α			
	Gate-to-Source Voltage	6				
V _{GS}	Gate-to-Source Voltage	-4	V			
	Gate-to-Source Voltage (Repetitive Transient) (1)	7				
Tر	Operating Temperature	-40 to 150)			
T _{STG}	Storage Temperature	-55 to 175				

⁽¹⁾ Pulsed repetitively, duty cycle factor (DC_{Factor}) ≤ 1%; Figure 13;

Thermal Characteristics					
	PARAMETER TYP UNIT				
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Case TOP)	0.5			
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board (Case BOTTOM)	2.8	°C/W		
R _{0JA_JEDEC}	Thermal Resistance, Junction-to-Ambient (using JEDEC 51-2 PCB)	54	C/W		
R _{0JA_EVB}	Thermal Resistance, Junction-to-Ambient (EPC90148 EVB)	23			

	Static Characteristics ($T_J = 25^{\circ}$ C unless otherwise stated)					
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV _{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, } I_D = 200 \mu\text{A}$	150			V
I _{DSS}	Drain-Source Leakage	$V_{GS} = 0 \text{ V}, V_{DS} = 120 \text{ V}$		0.01	0.2	
	Gate-to-Source Forward Leakage	$V_{GS} = 5 V$		0.015	2	
I _{GSS}	Gate-to-Source Forward Leakage#	$V_{GS} = 5 \text{ V, T}_{J} = 125^{\circ}\text{C}$		0.2	4	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 V$		0.1	1	
V _{GS(TH)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 5 \text{ mA}$	0.8	1.2	2.5	V
R _{DS(on)}	Drain-Source On Resistance	$V_{GS} = 5 \text{ V, } I_D = 15 \text{ A}$		4.5	6	mΩ
V _{SD}	Source-Drain Forward Voltage#	$V_{GS} = 0 \text{ V, } I_S = 0.5 \text{ A}$		1.5		V

[#] Defined by design. Not subject to production test.



Package size: 3 x 5 mm

EPC2308

- High density DC-DC from 80–100 V
- AC/DC
- Synchronous rectification from 28–54 V for chargers, adaptors, and power supplies
- · Solar optimizers and microinverters
- Motor drive and DC-DC for batteryoperated power tools and robots
- · USB fast chargers

Benefits

- Higher Efficiency Lower conduction and switching losses, zero reverse recovery losses
- Ultra small footprint Higher power density
- Thermally enhanced QFN package with exposed top and ultra-low thermal resistances for cooler operations
- Wettable flanks and 0.6 mm between high voltage and low voltage pads to simplify assembly and inspection

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



https://l.ead.me/EPC2308

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	Dynamic Characteristics# (T _J = 25°C unless otherwise stated)					
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
C _{ISS}	Input Capacitance			1667	2377	
C_{RSS}	Reverse Transfer Capacitance	$V_{DS} = 75 \text{ V}, V_{GS} = 0 \text{ V}$		3.1		
Coss	Output Capacitance			401	558	рF
C _{OSS(ER)}	Effective Output Capacitance, Energy Related (Note 1)	$V_{DS} = 0$ to 75 V, $V_{GS} = 0$ V		510		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 2)	VDS = 0 to 75 V, VGS = 0 V		665		
R_{G}	Gate Resistance			0.4		Ω
Q_{G}	Total Gate Charge	$V_{DS} = 75 \text{ V}, V_{GS} = 5 \text{ V}, I_{D} = 15 \text{ A}$		11.7	16	
Q_{GS}	Gate-to-Source Charge			4.2		
Q _{GD}	Gate-to-Drain Charge	$V_{DS} = 75 \text{ V, } I_D = 15 \text{ A}$		1		
Q _{G(TH)}	Gate Charge at Threshold	1		3		nC
Qoss	Output Charge	$V_{DS} = 75 \text{ V}, V_{GS} = 0 \text{ V}$		50	61	
Q _{RR}	Source-Drain Recovery Charge			0		

[#] Defined by design. Not subject to production test.

Figure 1: Typical Output Characteristics at 25°C

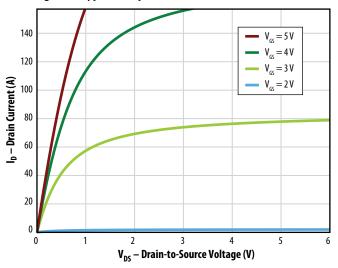


Figure 3: Typical $\rm R_{DS(on)}$ vs. $\rm V_{GS}$ for Various Drain Currents

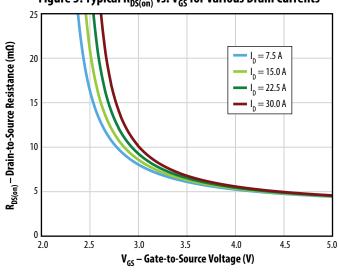
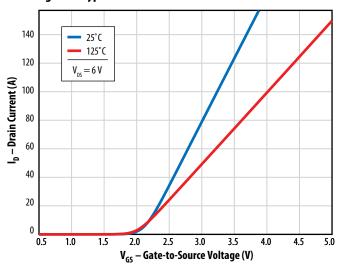
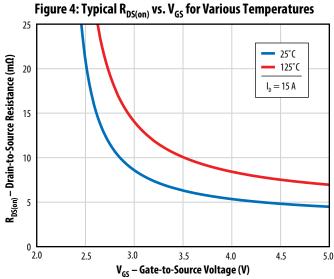


Figure 2: Typical Transfer Characteristics





All measurements were done with substrate connected to source. Note 1: $C_{OSS(IER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}. Note 2: $C_{OSS(ITR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.

Figure 5a: Typical Capacitance (Linear Scale)

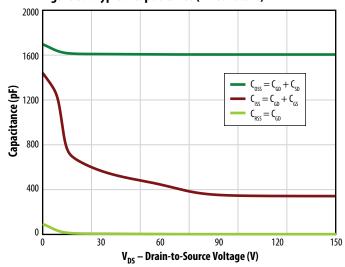


Figure 6: Typical Output Charge and Coss Stored Energy

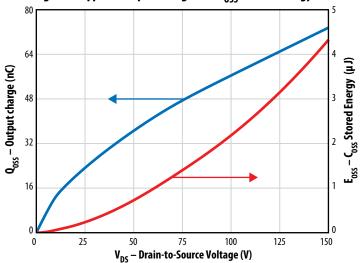
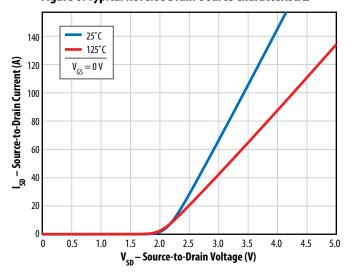


Figure 8: Typical Reverse Drain-Source Characteristics



Note: Negative gate drive voltage increases the reverse drain-source voltage. EPC recommends 0 V for OFF.

Figure 5b: Typical Capacitance (Log Scale)

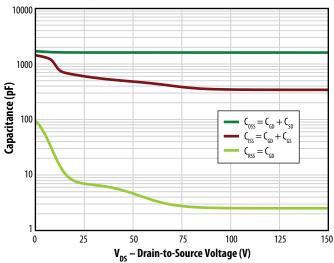


Figure 7: Typical Gate Charge

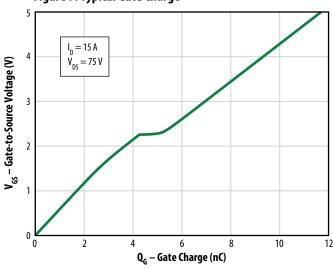


Figure 9: Typical Normalized On-State Resistance vs. Temp.

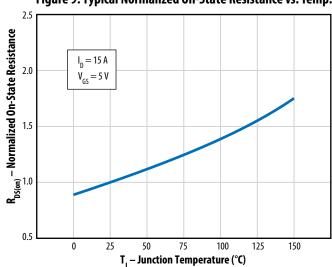
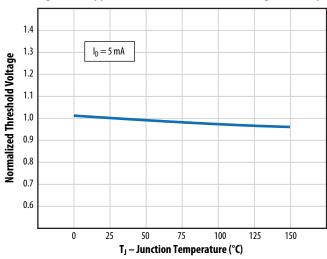


Figure 10: Typical Normalized Threshold Voltage vs. Temp.



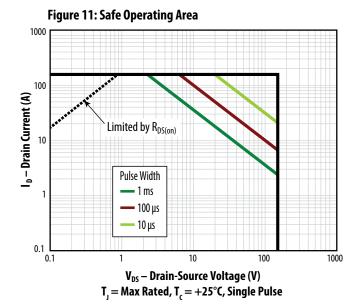
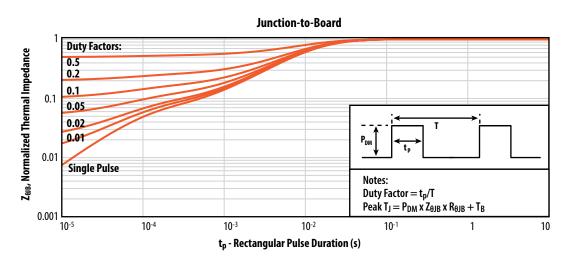


Figure 12: Typical Transient Thermal Response Curves



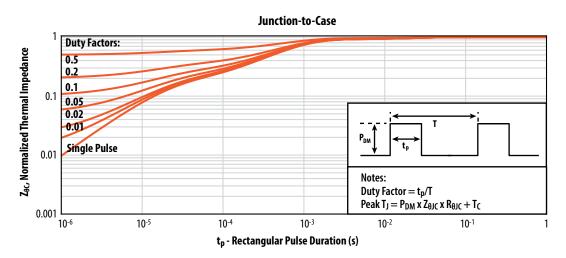
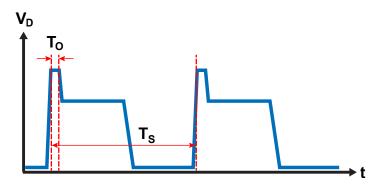


Figure 13: Duty Cycle Factor (DC_{Factor}) Illustration for Repetitive Overvoltage Specification



1% is the ratio between T_0 (overvoltage duration) and T_s (one switching period)

LAYOUT CONSIDERATIONS

GaN transistors generally behave like power MOSFETs, but at much higher switching speeds and power densities, therefore layout considerations are very important, and care must be taken to minimize layout parasitic inductances. The recommended design utilizes the first inner layer as a power loop return path. This return path is located directly beneath the top layer's power loop allowing for the smallest physical loop size. This method is also commonly referred to as flux cancellation. Variations of this concept can be implemented by placing the bus capacitors either next to the high side device, next to the low side device, or between the low and high side devices, but in all cases the loop is closed using the first inner layer right beneath the devices.

A similar concept is also used for the gate loop, with the first inner layer used as a reference for the gate loop under the gate resistors and the relative pins of the gate driver: ground for the bottom FET and switch node for the top FET.

Furthermore, to minimize the common source inductance between power and gate loops, the power and gate loops are laid out perpendicular to each other, and a via next to the source pad closest to the gate pad is used as Kelvin connection for the gate driver return path.

The EPC90148 Half-Bridge Development Board Using EPC2308 implements our recommended vertical inner layout.

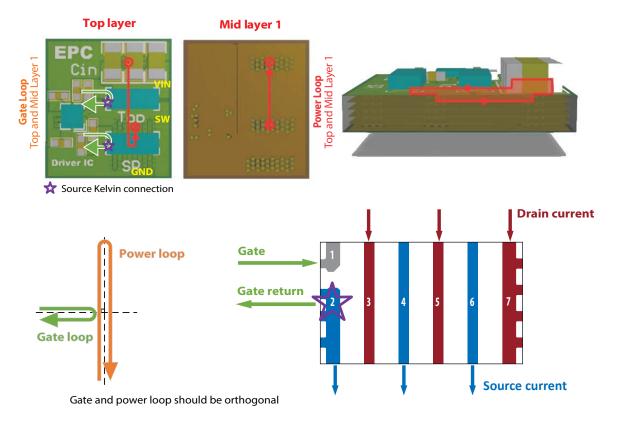


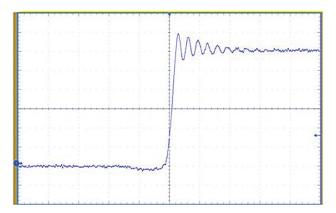
Figure 14: Inner Vertical Layout for Power and Gate Loops

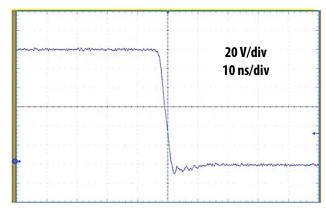
Detailed recommendations on layout can be found on EPC's website: Optimizing PCB Layout with eGaN FETs.pdf

TYPICAL SWITCHING BEHAVIOR

The following typical switching waveforms are captured in these conditions:

- EPC90148: 150 V, 12 A Half-Bridge Development Board Featuring EPC2308
- Gate driver: NCP51820 with 1A source and 2A sink capability
- External $R_G(ON) = 1 \Omega$, $R_G(OFF) = 0 \Omega$
- $V_{IN} = 120 \text{ V}$, $I_L = 30 \text{ A}$





Typical turn ON: 46 V/ns

Typical turn OFF: 28 V/ns

Figure 15: Typical half-bridge voltage switching waveforms

See the EPC90148 Half-Bridge Development Board Using EPC2308 Quick Start Guide for more information.

TYPICAL THERMAL CONCEPT

The EPC2308 can take advantage of dual sided cooling to maximize its heat dissipation capabilities in high power density designs. Note that the top of EPC FETs are connected to source potential, so for half-bridge topologies the Thermal Interface Material (TIM) needs to provide electrical isolation to the heatsink.

Recommended best practice thermal solutions are covered in detail in How2AppNote012 - How to Get More Power Out of an eGaN Converter.pdf.

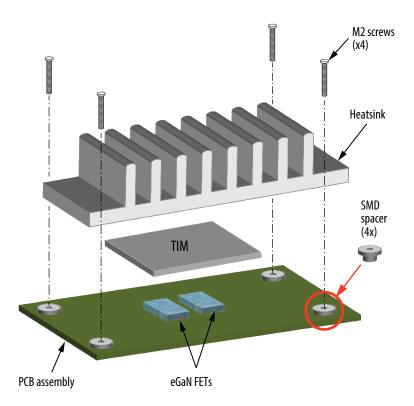


Figure 16: Exploded view of heatsink assembly using screws

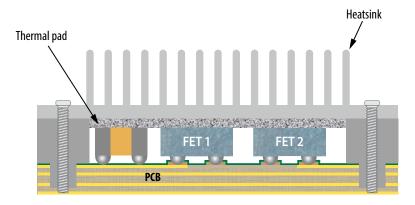
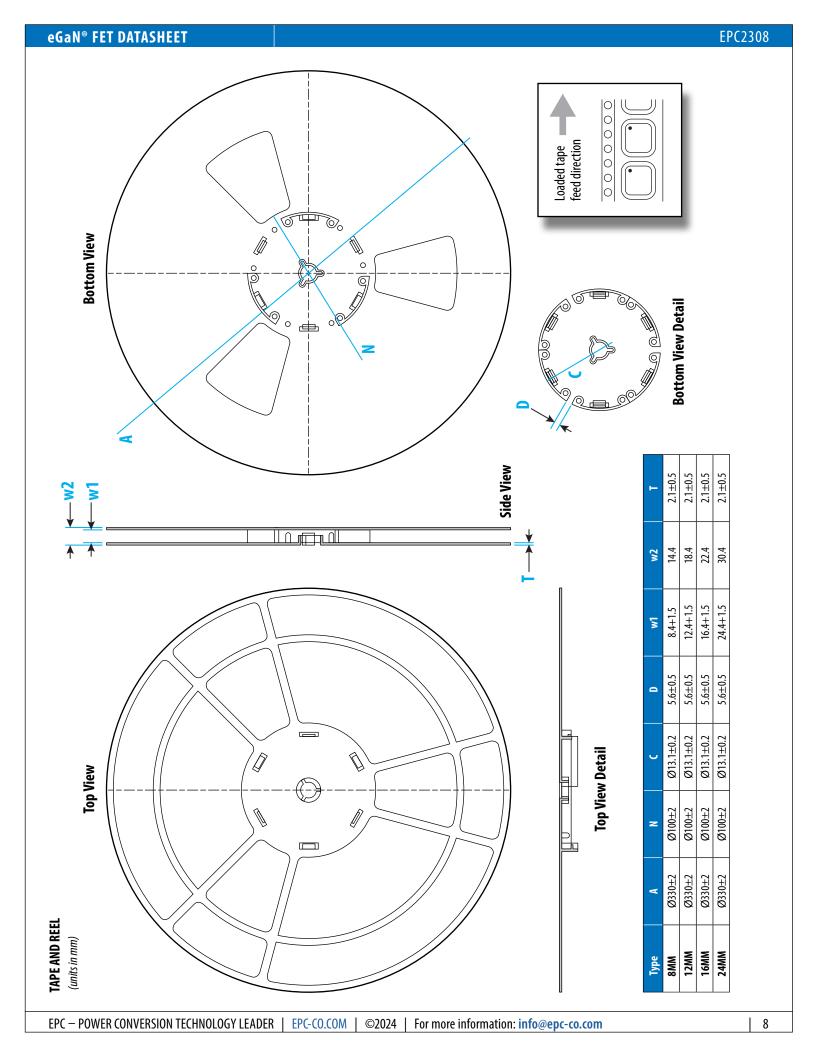


Figure 17: A cross-section image of dual sided thermal solution

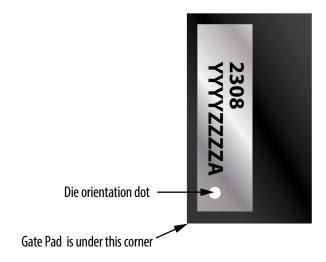
Note: Connecting the heatsink to ground is recommended and can significantly improve radiated EMI

The thermal design can be optimized by using the **GaN FET Thermal Calculator** on EPC's website.

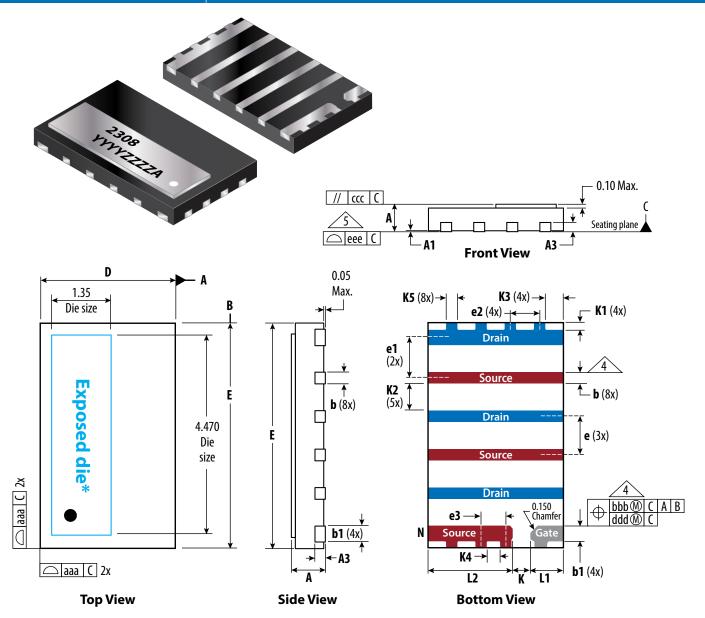


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Part Marking



Part	Laser Markings			
Number	Part # Marking Line 1	Lot_Date Code Marking Line 2		
EPC2308	2308	YYYYZZZZA		



*The exposed die is the silicon substrate that is internally connected to the source. It is not recommended to use it as an electrical connection

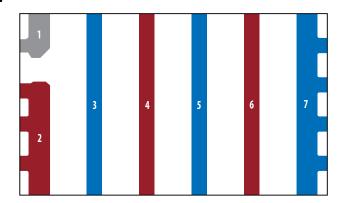
CVMDOL	Dimension (mm)				
SYMBOL	MIN	Nominal	MAX	Note	
A			0.70		
A1	0.00	0.02	0.05		
A3			0.25		
b	0.20	0.25	0.30	4	
b1	0.30	0.35	0.40	4	
D	2.90	3.00	3.10		
E	4.90	5.00	5.10		
e	e 0.85 BSC				
e1	0.90 BSC				
e2	0.65 BSC				
e3	0.55 BSC				
L1	0.625	0.725	0.825		
L2	1.775	1.875	1.975		

SYMBOL		Dimension	(mm)	
STMIDUL	MIN	Nominal	MAX	Note
K		0.40 Ref		
K1		0.15 Ref		
K2		0.60 Ref		
К3		0.40 Ref		
K4				
K5				
aaa	0.05			
bbb				
ССС	0.10			
ddd				
eee	0.08			
N		3		

Notes:

- 1. Dimensioning and tolerancing conform to ASME Y14.5-2009
- 2. All dimensions are in millimeters
- 3. **N** is the total number of terminals
- 4. Dimension **b** applies to the metalized terminal and a radius on the other end of it, dimension **b** should not be measured in that radius area.
- 5. Coplanarity applies to the terminals and all the other bottom surface metallization.

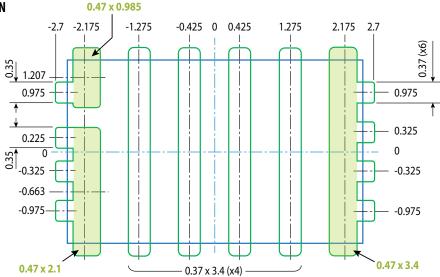
TRANSPARENT VIEW



PIN	Description	
1	Gate	
2	Source	
3	Drain	
4	Source	
5	Drain	
6	Source	
7	Drain	

RECOMMENDED LAND PATTERN

(units in mm)



Land pattern is solder mask defined.

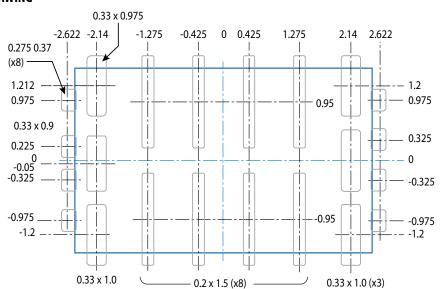
Legend:

Part outline Mask opening

Radius = 0.05

RECOMMENDED STENCIL DRAWING

(units in mm)



Legend:

Part outline

Stencil opening

Recommended stencil should be 4 mil (100 µm) thick, must be laser cut, openings per drawing. Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

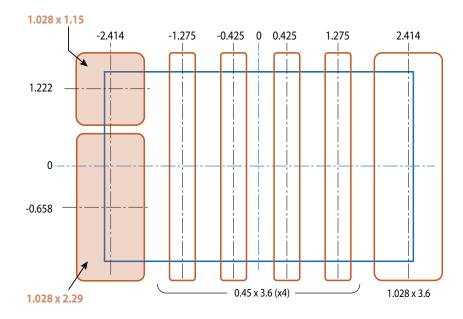
The corner has a radius of R60.

Split stencil design can be provided upon request, but EPC has tested this stencil design and not found any scooping issues.

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RECOMMENDED COPPER DRAWING

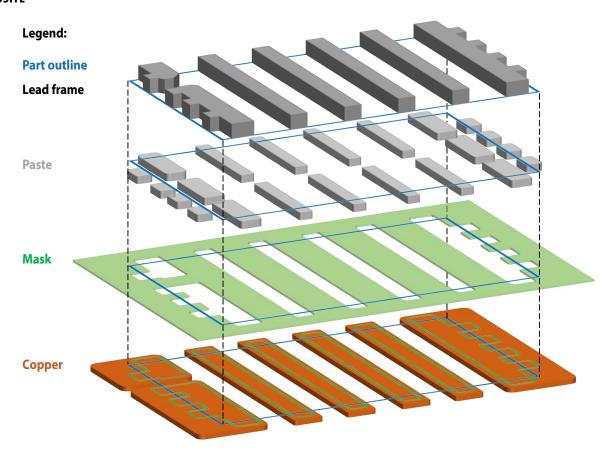
(units in mm)



Legend: **Part outline** Copper

Radius = 0.05

3D COMPOSITE



ADDITIONAL RESOURCES AVAILABLE

Solder mask defined pads are recommended for best reliability.

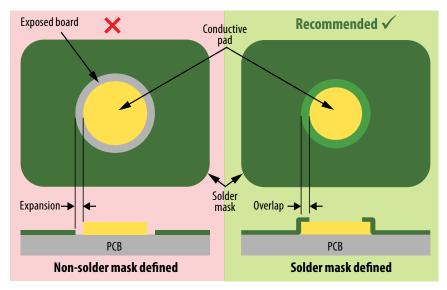


Figure 17: Solder mask defined versus non-solder mask defined pad

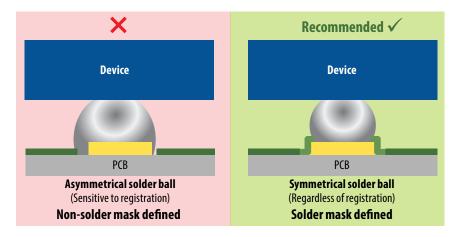


Figure 18: Effect of solder mask design on the solder ball symmetry

Additional resources available

- $\bullet \ Assembly \ resources-https://epc-co.com/epc/Portals/0/epc/documents/product-training/Appnote_GaNassembly.pdf$
- Library of Altium footprints for production FETs and ICs https://epc-co.com/epc/documents/altium-files/EPC%20Altium%20Library.zip (for preliminary device Altium footprints, contact EPC)

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 $\hbox{EPC Patent Listing: https://epc-co.com/epc/about-epc/patents}$

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